

| | | |
|---|--|---|
| Search Notes  | Application/Control No. 10/630,949 | Applicant(s)/Patent under Reexamination REED ET AL. |
| | Examiner Hiep Nguyen | Art Unit 2816 |
| | | |

| SEARCHED | | | |
|--------------|----------|----------|----------|
| Class | Subclass | Date | Examiner |
| 327 | 323 | 11.07.04 | Mar |
| | 108 | — | — |
| 326 | 80 | — | — |
| 361 | 91.1 | ↓ | ↓ |
| All Searches | | 01.28.05 | Mar |
| Unrelated | | — | — |
| 327 | 306 | — | — |
| | 318 | — | — |
| 361 | 56 | — | — |
| | 91.7 | — | — |
| | 93.9 | ↓ | — |
| | | | |
| | | | |
| | | | |
| | | | |

| INTERFERENCE SEARCHED | | | |
|-----------------------|----------|----------|----------|
| Class | Subclass | Date | Examiner |
| 327 | 323 | 01-28.05 | Ha |
| 361 | 91.1 | T | T |
| | 91.7 | ↓ | ↓ |
| | | | |